

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Takashi FUJITA et al.**

Art Unit: **1797**

Application Number: **10/561,538**

Examiner: **Xiaoyun Xu**

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For: **SPECIFIC COMPONENT MEASURING METHOD BY SPECTRAL
MEASUREMENT**

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STATEMENT UNDER 37 CFR §1.704(d)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 22, 2010

Sir:

Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. A copy of each non- U.S. document is attached.

Each listed document was first cited in a communication from a foreign patent office and the communication was not received by any person defined in 37 C.F.R. §1.56(c) more than 30 days before filing of this paper.

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Respectfully submitted,
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Enclosures: PTO/SB/08; Foreign Communication; 2 Documents